

**Search Notes**

Application/Control No.

10/525,410

Examiner

Karen Cheng

Applicant(s)/Patent under  
Reexamination

FENG ET AL.

Art Unit

1626

**SEARCHED**

Class	Subclass	Date	Examiner
548	311.1	1/4/2007	KC
548	315.4	1/4/2007	KC
548	347.1	1/4/2007	KC
548	355.1	1/4/2007	KC
549	429	1/4/2007	KC
549	460	1/4/2007	KC
514	397	2/28/2007	KC
548	311.7	2/28/2007	KC
514	383	2/28/2007	KC
514	422	2/28/2007	KC
548	266.4	2/28/2007	KC
548	526	2/28/2007	KC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
514	311.7	2/28/2007	KC
514	383	2/28/2007	KC
514	422	2/28/2007	KC
548/ 311.7, 266.4, 526		2/28/2007	KC

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
STN Structure Search (see attached)	1/4/2007	KC
EAST Search (see attached)	1/4/2007	KC
Inventor Name Search	1/4/2007	KC
STN Structure Search (updated, see attached)	2/28/2007	KC
EAST Search (see attached)	2/28/2007	KC